

# N-Channel 150 V (D-S) MOSFET

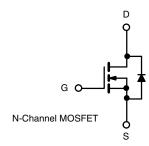
PRODUCT SUMMARY				
V <sub>DS</sub> (V)	150			
$R_{DS(on)} (\Omega)$ at $V_{GS} = 10 V$	0.075			
I <sub>D</sub> (A)	20			
Configuration	Single			
Package	TO-220			



### FEATURES

- TrenchFET<sup>®</sup> power MOSFET
- Package with low thermal resistance
- + 100 %  $\rm R_g$  and UIS tested





<b>ABSOLUTE MAXIMUM RATINGS</b> ( $T_C = 25 \degree C$ , unless otherwise noted)						
PARAMETER		SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V <sub>DS</sub>	150	V		
Gate-Source Voltage		V <sub>GS</sub>	± 20	v		
Continuous Drain Current	T <sub>C</sub> = 25 °C	I-	20			
	T <sub>C</sub> = 125 °C	- I <sub>D</sub>	14			
Continuous Source Current (Diode Conduction) a		I <sub>S</sub>	50	А		
Pulsed Drain Current <sup>b</sup>		I <sub>DM</sub>	60			
Single Pulse Avalanche Energy	L = 0.1 mH	I <sub>AS</sub>	30			
Single Pulse Avalanche Current		E <sub>AS</sub>	45	mJ		
Maximum Power Dissipation <sup>b</sup>	T <sub>C</sub> = 25 °C	PD	107	W		
	T <sub>C</sub> = 125 °C	гD	35	٧V		
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C			

THERMAL RESISTANCE RATINGS						
PARAMETER		SYMBOL	LIMIT	UNIT		
Junction-to-Ambient	PCB Mount <sup>c</sup>	R <sub>thJA</sub>	50	°C/W		
Junction-to-Case (Drain)	on-to-Case (Drain)		1.4	0/10		

Notes

- a. Package limited.
- b. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %.
- c. When mounted on 1" square PCB (FR4 material).
- d. Parametric verification ongoing.

		<b>SPECIFICATIONS</b> ( $T_C = 25$ °C, unless otherwise noted)							
PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT		
Static									
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 V, I_D = 250 \mu A$		150	-	-	v		
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =	$V_{DS} = V_{GS}$ , $I_D = 250 \ \mu A$		-	3.5	v		
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{GS} = \pm 20 V$		-	-	± 100	nA		
		$V_{GS} = 0 V$	V <sub>DS</sub> = 150 V	-	-	1			
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V$	$V_{DS}$ = 150 V, $T_J$ = 125 °C	-	-	50	μA		
		$V_{GS} = 0 V$	$V_{DS}$ = 150 V, T <sub>J</sub> = 175 °C	-	-	250			
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{GS} = 10 V$	$V_{DS} \ge 5 V$	30	-	-	А		
		$V_{GS} = 10 V$	I <sub>D</sub> = 12 A	-	0.075	-	Ω		
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 10 V$	I <sub>D</sub> = 12 A, T <sub>J</sub> = 125 °C	-	0.116	-			
		$V_{GS} = 10 V$	I <sub>D</sub> = 12 A, T <sub>J</sub> = 175 °C	-	0.158	-			
Forward Transconductance <sup>b</sup>	9 <sub>fs</sub>	$V_{DS} = 12 \text{ V}, \text{ I}_{D} = 15 \text{ A}$		-	33	-	S		
Dynamic <sup>b</sup>									
Input Capacitance	C <sub>iss</sub>			-	1090	1660			
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0 V$	V <sub>DS</sub> = 25 V, f = 1 MHz	-	165	200	pF		
Reverse Transfer Capacitance	C <sub>rss</sub>			-	82	120			
Total Gate Charge <sup>c</sup>	Qg			-	27	50			
Gate-Source Charge <sup>c</sup>	Q <sub>gs</sub>	$V_{GS} = 10 V$	$V_{DS} = 75 \text{ V}, \text{ I}_{D} = 20 \text{ A}$	-	7.5	-	nC		
Gate-Drain Charge <sup>c</sup>	Q <sub>gd</sub>				10.2	-			
Gate Resistance	R <sub>g</sub>	f = 1 MHz		0.35	1.0	3.2	Ω		
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>			-	11	17			
Rise Time <sup>c</sup>	t <sub>r</sub>	$V_{DD}$ = 75 V, R <sub>L</sub> = 3 $\Omega$ I <sub>D</sub> $\cong$ 20A, V <sub>GEN</sub> = 10 V, R <sub>g</sub> = 1 $\Omega$		-	21	33	ns		
Turn-Off Delay Time <sup>c</sup>	t <sub>d(off)</sub>			-	20	30			
Fall Time <sup>c</sup>	t <sub>f</sub>			-	12	20			
Source-Drain Diode Ratings and Characteristics <sup>b</sup>									
Pulsed Current <sup>a</sup>	I <sub>SM</sub>			-	-	65	Α		
Forward Voltage	V <sub>SD</sub>	I <sub>F</sub> = 20 A, V <sub>GS</sub> = 0 V		-	0.85	1.5	V		

#### Notes

a. Pulse test; pulse width  $\leq$  300 µs, duty cycle  $\leq$  2 %.

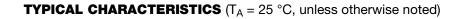
b. Guaranteed by design, not subject to production testing.

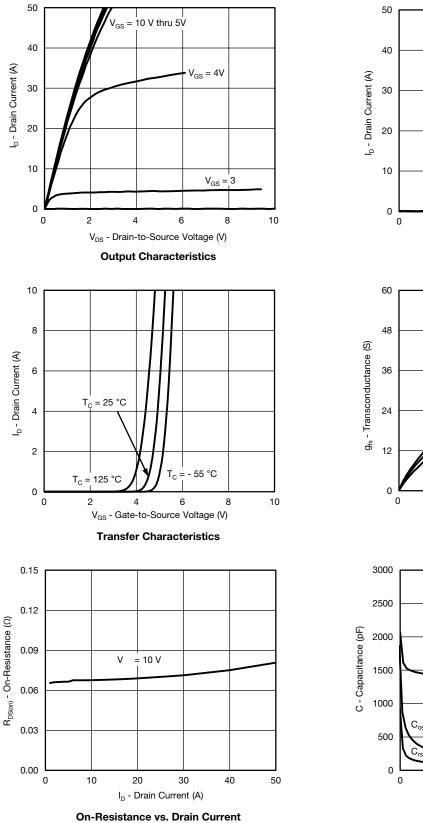
c. Independent of operating temperature.

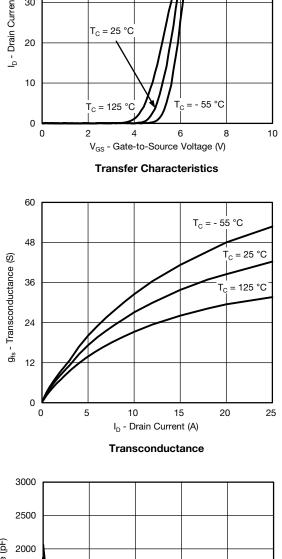
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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C<sub>iss</sub>

15

30

45

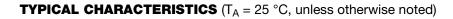
V<sub>DS</sub> - Drain-to-Source Voltage (V)

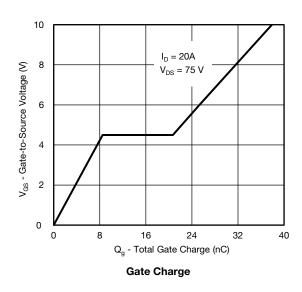
Capacitance

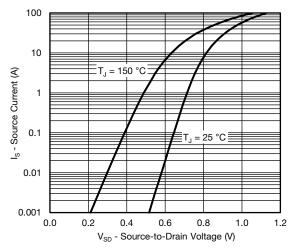
60

75

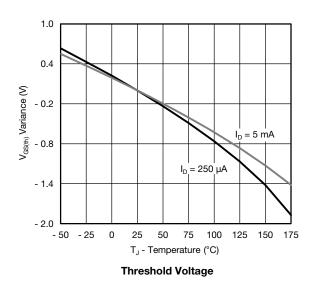


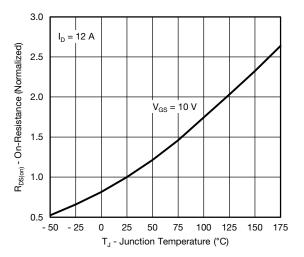




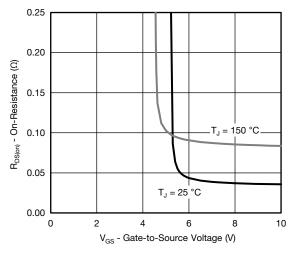


Source Drain Diode Forward Voltage

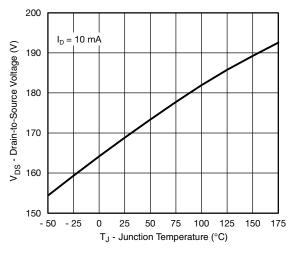




**On-Resistance vs. Junction Temperature** 



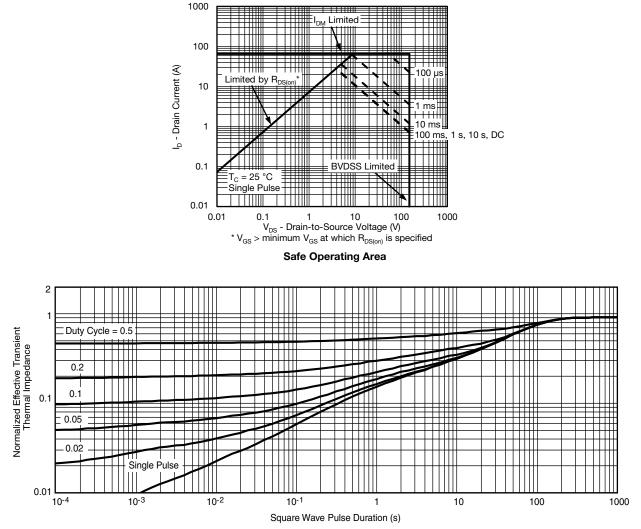
**On-Resistance vs. Gate-to-Source Voltage** 



Drain Source Breakdown vs. Junction Temperature



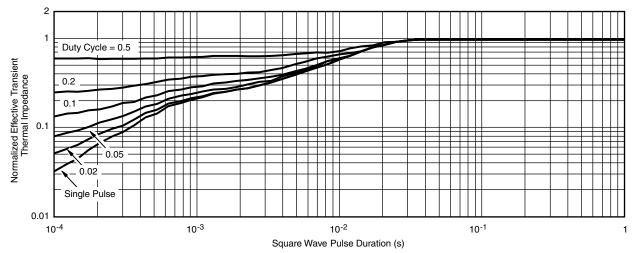
## **THERMAL RATINGS** (T<sub>A</sub> = 25 °C, unless otherwise noted)







## **THERMAL RATINGS** ( $T_A = 25 \text{ °C}$ , unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Case

#### Note

• The characteristics shown in the two graphs

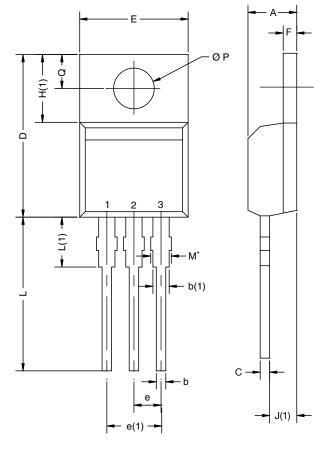
- Normalized Transient Thermal Impedance Junction to Ambient (25 °C)

- Normalized Transient Thermal Impedance Junction to Case (25 °C)

are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions.



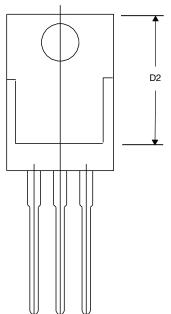
# **TO-220AB**



	MILLIMETERS		INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
D2	12.19	12.70	0.480	0.500	
E	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØΡ	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: T14-0413-Rev. P, 16-Jun-14 DWG: 5471					

## Note

\* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM





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